

<b>Notice of References Cited</b>	Application/Control No. 10/010,779	Applicant(s)/Patent Under Reexamination EISENSTEIN, JONATHAN	
	Examiner Tan Dean D. Nguyen	Art Unit 3629	Page 1 of 1

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*	B	US-2002/0010636	01-2002	Immel, John J.	705/26
*	C	US-2001/0037206	11-2001	Falk et al.	705/1
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	K	US-			
	L	US-			
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**NON-PATENT DOCUMENTS**

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